# 1 Mbit (128K x 8) nvSRAM With Real-Time Clock

#### **Features**

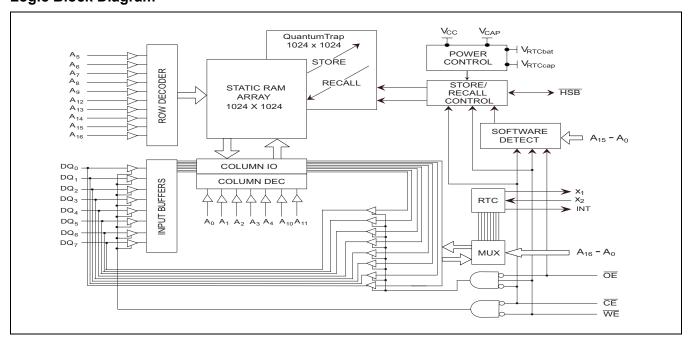
- Data integrity of Cypress nvSRAM combined with full featured Real-Time Clock (RTC)
- · Watchdog timer
- · Clock alarm with programmable interrupts
- · Capacitor or battery backup for RTC
- 25 ns, 35 ns, and 45 ns access times
- "Hands-off" automatic STORE on power down with only a small capacitor
- STORE to QuantumTrap™ initiated by software, device pin, or on power down
- RECALL to SRAM initiated by software or on power up
- Infinite READ, WRITE, and RECALL cycles
- · High reliability
  - Endurance to 200,000 cycles
  - Data retention: 20 years @55°C
- 10 mA typical I<sub>CC</sub> at 200 ns cycle time
- Single 3V operation +20%, -10%
- · Commercial and industrial temperature
- SSOP package (ROHS compliant)

## **Functional Description**

The Cypress CY14B101K combines a 1 Mbit nonvolatile static RAM with a full featured real-time clock in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap technology producing the world's most reliable nonvolatile memory. The SRAM can be read and written an infinite number of times, while independent, nonvolatile data resides in the nonvolatile elements.

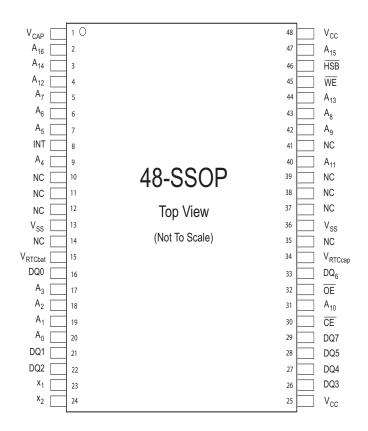
The Real-Time Clock function provides an accurate clock with leap year tracking and a programmable, high accuracy oscillator. The alarm function is programmable for one time alarm or periodic seconds, minutes, hours, or days. There is also a programmable watchdog timer for process control.

# Logic Block Diagram





# **Pin Configurations**



# **Pin Definitions**

Pin Name	IO Type	Description
$A_0 - A_{16}$	Input	Address inputs used to select one of the 131,072 bytes of the nvSRAM.
DQ0 – DQ7	Input Output	Bidirectional data IO lines. Used as input or output lines depending on operation
NC	No Connect	No Connects. This pin is not connected to the die
WE	Input	<b>Write Enable Input, active LOW</b> . When selected LO <u>W</u> , enables data on the IO pins to be written to the address location latched by the falling edge of CE.
CE	Input	Chip Enable Input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌĒ	Input	Output Enable, active LOW. The active low OE input enables the data output buffers during READ cycles. Deasserting OE high causes the IO pins to tri-state.
X <sub>1</sub>	Output	Crystal connection, drives crystal on start up.
X <sub>2</sub>	Input	Crystal connection for 32.768 kHz crystal.
V <sub>RTCcap</sub>	Power Supply	Capacitor supplied backup RTC supply voltage. (Left unconnected if V <sub>RTCbat</sub> is used)
V <sub>RTCbat</sub>	Power Supply	Battery supplied backup RTC supply voltage. (Left unconnected if V <sub>RTCcap</sub> is used)
INT	Output	Interrupt Output. Program to respond to the clock alarm, the watchdog timer and the power monitor. Programmable to either active HIGH (push/pull) or LOW (open drain).
V <sub>SS</sub>	Ground	Ground for the device. Must be connected to ground of the system.
V <sub>CC</sub>	Power Supply	Power Supply inputs to the device.
HSB	Input Output	<b>Hardware Store Busy</b> . When LOW this output indicates a Hardware Store is in progress. When pulled low external to the chip it initiates a nonvolatile STORE operation. A weak internal pull up resistor keeps this pin HIGH if not connected (connection optional).
V <sub>CAP</sub>	Power Supply	<b>AutoStore</b> <sup>TM</sup> <b>Capacitor.</b> Supplies power to nvSRAM during power loss to store data from SRAM to nonvolatile elements.



### **Device Operation**

The CY14B101K nvSRAM is made up of two functional components paired in the same physical cell, a SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Transfer of the data can be from the SRAM to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to SRAM (the RECALL operation). This unique architecture allows all cells to be stored and recalled in parallel. During the STORE and RECALL operations SRAM READ and WRITE operations are inhibited. The CY14B101K supports infinite reads and writes just like a typical SRAM. In addition, it provides infinite RECALL operations from the nonvolatile cells and up to 200,000 STORE operations.

#### **SRAM READ**

The CY14B101K performs a READ cycle whenever CE and OE are low, while WE and HSB are high. The address specified on pins  $A_{0-16}$  determines which of the 131,072 data bytes will be accessed. When the READ is initiated by an address transition, the outputs will be valid after a delay of  $t_{AA}$  (READ cycle 1). If the READ is initiated by CE or OE, the outputs will be valid at  $t_{ACE}$  or at  $t_{DOE}$ , whichever is later (READ cycle 2). The data outputs repeatedly responds to address changes within the  $t_{AA}$  access time without the need for transitions on any control input pins. It remains valid until another address change, or until CE or OE is brought high, or WE or HSB is brought low.

#### **SRAM WRITE**

A WRITE cycle is performed whenever  $\overline{\text{CE}}$  and  $\overline{\text{WE}}$  are low and HSB is high. The address inputs must be stable before entering the WRITE cycle and must remain stable until either  $\overline{\text{CE}}$  or  $\overline{\text{WE}}$  goes high, at the end of the cycle. The data on the common IO pins DQ $_{0-7}$  will be written into the memory if the data is valid  $t_{SD}$  before the end of a WE-controlled WRITE or before the end of an  $\overline{\text{CE}}$ -controlled WRITE. It is recommended that  $\overline{\text{OE}}$  be kept high during the entire WRITE cycle to avoid data bus contention on common IO lines. If  $\overline{\text{OE}}$  is left  $\overline{\text{Iow}}$ , internal circuitry turns off the output buffers  $t_{HZWE}$  after  $\overline{\text{WE}}$  goes low.

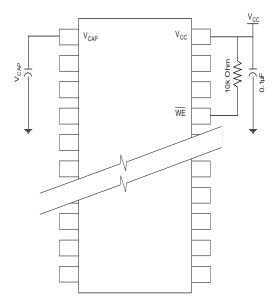
#### **AutoStore Operation**

The CY14B101K stores data to nvSRAM using one of three storage operations. These three operations are Hardware Store activated by HSB, Software Store activated by an address sequence, and AutoStore on device power down. AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B101K.

During normal operation, the device draws current from  $V_{CC}$  to charge a capacitor connected to the  $V_{CAP}$  pin. This stored charge will be used by the chip to perform a single STORE operation. If the voltage on the  $V_{CC}$  pin drops below  $V_{SWITCH}$ , the part automatically disconnects the  $V_{CAP}$  pin from  $V_{CC}$ . A STORE operation will be initiated with power provided by the  $V_{CAP}$  capacitor.

Figure 1 shows the proper connection of the storage capacitor ( $V_{CAP}$ ) for automatic store operation. Refer to the Table , "DC Electrical Characteristics," on page 14 for the size of  $V_{CAP}$ 

Figure 1. AutoStore Mode



The voltage on the  $V_{CAP}$  pin is driven to 5V by a <u>charge</u> pump internal to the chip. A pull up must be placed on WE to hold it inactive during power up.

To reduce unnecessary nonvolatile stores, AutoStore and Hardware Store operations will be ignored unless at least one WRITE operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a WRITE operation has taken place. Monitor the HSB signal by the system to detect if an AutoStore cycle is in progress.

# Hardware STORE (HSB) Operation

The CY14B101K provides the  $\overline{\text{HSB}}$  pin for controlling and acknowledging the STORE operations. Use the  $\overline{\text{HSB}}$  pin to request a hardware STORE cycle. When the  $\overline{\text{HSB}}$  pin is driven low, the CY14B101K conditionally initiates a STORE operation after t<sub>DELAY</sub>. An actual STORE cycle only begins if a WRITE to the SRAM took place since the last STORE or RECALL cycle. The  $\overline{\text{HSB}}$  pin also acts as an open drain driver that is internally driven low to indicate a busy condition while the STORE (initiated by any means) is in progress.

SRAM\_READ and WRITE operations that are in progress when HSB is driven low by any means are given time to complete before the STORE operation is initiated. After HSB goes low, the CY14B101K continues SRAM operations for  $t_{\mbox{\scriptsize DELAY}}$ . During  $t_{\mbox{\scriptsize DELAY}}$ , multiple SRAM READ operations may take place. If a WRITE is in progress when HSB is pulled low it will be allowed a time,  $t_{\mbox{\scriptsize DELAY}}$ , to complete. However, any SRAM WRITE cycles requested after HSB goes low will be inhibited until HSB returns high.

During any STORE operation, regardless of <a href="https://how.nc



## Hardware RECALL (Power Up)

During power up, or after any low power condition ( $V_{CC} < V_{SWITCH}$ ), an internal RECALL request will be latched. When  $V_{CC}$  once again exceeds the sense voltage of  $V_{SWITCH}$ , a RECALL cycle will be automatically initiated and takes  $t_{HRECALL}$  to complete.

#### **Software STORE**

Using a software address sequence, transfer the data from the SRAM to the nonvolatile memory. The CY14B101K software STORE cycle is initiated by executing sequential CE-controlled READ cycles from six specific address locations in exact order. During the STORE cycle an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. Once a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for STORE initiation, it is important that no other READ or WRITE accesses intervene in the sequence. If there are intervening READ OR WRITE accesses, the sequence will be aborted and no STORE or RECALL takes place.

To initiate the software STORE cycle, the following READ sequence must be performed:

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x8FC0 Initiate STORE cycle

The software sequence may be clocked with CE-controlled READs or OE-controlled READs. Once the sixth address in the sequence has been entered, the STORE cycle commences and the chip will be disabled. It is important that READ cycles and not WRITE cycles be used in the sequence. It is not necessary that OE be low for the sequence to be valid. After the t<sub>STORE</sub> cycle time has been fulfilled, the SRAM will again be activated for READ and WRITE operation.

#### Software RECALL

Transfer the data from the nonvolatile memory to the SRAM by a software address sequence. A software RECALL cycle is initiated with a sequence of READ operations in a manner similar to the software STORE initiation. To initiate the RECALL cycle, the following sequence of CE-controlled READ operations must be performed:

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x4C63 Initiate RECALL Cycle

Internally, RECALL is a two-step procedure. First, the SRAM data is cleared, and second, the nonvolatile information is

transferred into the SRAM cells. After the  $t_{RECALL}$  cycle time the SRAM will once again be ready for READ and WRITE operations. The RECALL operation does not alter the data in the nonvolatile elements.

#### **Preventing AutoStore**

Disable the AutoStore function by initiating an AutoStore Disable sequence. A sequence of READ operations is performed in a manner similar to the software STORE initiation. To initiate the AutoStore Disable sequence, the following sequence of CE-controlled READ operations must be performed:

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x8B45 AutoStore Disable

Re-enable the AutoStore by initiating an AutoStore Enable sequence. A sequence of READ operations is performed in a manner similar to the software RECALL initiation. To initiate the AutoStore Enable sequence, the following sequence of CE-controlled READ operations must be performed:

- 1. Read Address 0x4E38 Valid READ
- 2. Read Address 0xB1C7 Valid READ
- 3. Read Address 0x83E0 Valid READ
- 4. Read Address 0x7C1F Valid READ
- 5. Read Address 0x703F Valid READ
- 6. Read Address 0x4B46 AutoStore Enable

If the AutoStore function is disabled or re-enabled a manual STORE operation (Hardware or Software) needs to be issued to save the AutoStore state through subsequent power down cycles. The part comes from the factory with AutoStore enabled.

#### **Data Protection**

The CY14B101K protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and WRITE operations. The low voltage condition is detected when  $V_{CC} < V_{SWITCH}$ . If the CY14B101K is in a WRITE mode (both  $\overline{CE}$  and  $\overline{WE}$  low) at power up, after a RECALL, or after a STORE, the WRITE will be inhibited until a negative transition on  $\overline{CE}$  or  $\overline{WE}$  is detected. This protects against inadvertent writes during power up or brownout conditions.

#### **Noise Considerations**

The CY14B101K is a high-speed memory and so must have a high-frequency bypass capacitor of approximately 0.1  $\mu F$  connected between  $V_{CC}$  and  $V_{SS}$ , using leads and traces that are as short as possible. As with all high-speed CMOS ICs, careful routing of power, ground, and signals reduces circuit noise.



**Table 1. Mode Selection** 

CE	WE	ŌĒ	A15 – A0	Mode	Ю	Power
Н	Х	Х	Х	Not Selected	Output High-Z	Standby
L	Н	L	X	READ SRAM	Output Data	Active
L	L	Х	X	WRITE SRAM	Input Data	Active
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8B45	READ SRAM READ SRAM READ SRAM READ SRAM READ SRAM Autostore Disable	Output Data	Active <sup>[1, 2, 3]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4B46	READ SRAM READ SRAM READ SRAM READ SRAM Read SRAM Autostore Enable	Output Data	Active <sup>[1, 2, 3]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Store	Output Data Output Data Output Data Output Data Output Data Output Data Output High-Z	Active I <sub>CC2</sub> <sup>[1, 2, 3]</sup>
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Recall	Output Data Output Data Output Data Output Data Output Data Output High-Z	Active <sup>[1, 2, 3]</sup>

#### Notes

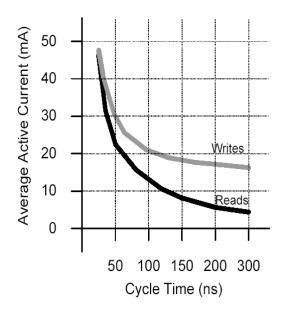
- The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.
   While there are 17 address lines on the CY14B101K, only the lower 16 lines are used to control software modes.
   IO state depends on the state of OE. The IO table shown is based on OE Low.



## **Low Average Active Power**

CMOS technology provides the CY14B101K, the benefit of drawing significantly less current when it is cycled at times longer than 50 ns. *Figure 2* on page 6 shows the relationship

Figure 2. Current vs. Cycle Time



between  $I_{CC}$  and READ/WRITE cycle time. Worst case current consumption is sREADhown for commercial temperature range,  $V_{CC}$  = 3.6V, and chip enable at maximum frequency. Only standby current is drawn when the chip is disabled.

The overall average current drawn by the CY14B101K depends on the following items:

- 1. The duty cycle of chip enable.
- 2. The overall cycle rate for accesses.
- 3. The ratio of READs to WRITEs.
- 4. The operating temperature.
- 5. The V<sub>CC</sub> level.
- 6. IO loading.

### Real-Time Clock Operation

#### nvTIME Operation

The CY14B101K offers internal registers that contain clock, alarm, watchdog, interrupt, and control functions. Internal double buffering of the clock and the clock/timer information registers prevents accessing transitional internal clock data during a READ or WRITE operation. Double buffering also circumvents disrupting normal timing counts or clock accuracy of the internal clock while accessing clock data. Clock and Alarm Registers store data in BCD format.

### **Clock Operations**

The clock registers maintain time up to 9,999 years in one second increments. The user can set the time to any calendar time and the clock automatically keeps track of days of the week, month, leap years, and century transitions. There are

eight registers dedicated to the clock functions that are used to set time with a WRITE cycle and to READ time during a READ cycle. These registers contain the Time of Day in BCD format. Bits defined as "0" are currently not used and are reserved for future use by Cypress.

#### Reading the Clock

While the double-buffered RTC register structure reduces the chance of reading incorrect data from the clock, you have to halt internal updates to the CY14B101K clock registers before reading clock data to prevent the reading of data in transition. Stopping the internal register updates does not affect clock accuracy. The update process is stopped by writing a "1" to the READ bit "R" (in the flags register at 0x1FFF0), and will not restart until a "0" is written to the READ bit. The RTC registers can then be READ while the internal clock continues to run. Within 20 ms after a "0" is written to the READ bit, all CY14B101K registers are simultaneously updated.

#### **Setting the Clock**

Setting the WRITE bit "W" (in the flags register at 0x1FFF0) to a "1" halts updates to the CY14B101K registers. The correct day, date, and time can then be written into the registers in 24-hour BCD format. The time written is referred to as the "Base Time." This value is stored in nonvolatile registers and used in calculation of the current time. Resetting the WRITE bit to "0" transfers those values to the actual clock counters, after which the clock resumes normal operation.

#### **Backup Power**

The RTC in the CY14B101K is intended for permanently powered operation. Either the  $V_{RTCcap}$  or  $V_{RTCbat}$  pin is connected depending on whether a capacitor or battery is chosen for the application. When primary power,  $V_{CC}$ , fails and drops below  $V_{SWITCH}$  the device will switch to the backup power supply.

The clock oscillator uses very little current which maximizes the backup time available from the backup source. Regardless of clock operation with the primary source removed, the data stored in nvSRAM is secure, having been stored in the nonvolatile elements as power was lost.

During backup operation the CY14B101K consumes a maximum of 300 nA at 2 volts. Capacitor or battery values must be chosen according to the application.

Backup time values based on maximum current specs are shown in the following table. Nominal times are approximately three times longer.

Table 2. RTC Backup Time

Capacitor Value	Backup Time
0.1F	72 hours
0.47F	14 days
1.0F	30 days

Using a capacitor has the obvious advantage of recharging the backup source each time the system is powered up. If a battery is used, a 3V lithium is recommended and the CY14B101K will only source current from the battery when the primary power is removed. The battery will not however be



recharged at any time by the CY14B101K. The battery capacity should be chosen for total anticipated cumulative downtime required over the life of the system.

#### Stopping and Starting the Oscillator

The OSCEN bit in the calibration register at 0x1FFF8 controls the starting and stopping of the oscillator. This bit is nonvolatile and shipped to customers in the "enabled" (set to 0) state. To preserve battery life while system is in storage, OSCEN should be set to a 1. This turns off the oscillator circuit extending the battery life. If the OSCEN bit goes from disabled to enabled, it takes approximately 5 seconds (10 seconds max) for the oscillator to start.

The CY14B101K has the ability to detect oscillator failure. This is recorded in the OSCF (Oscillator Failed bit) of the flags register at address 0x1FFF0. When the device is powered on ( $V_{CC}$  goes above  $V_{SWITCH}$ ) the  $\overline{OSCEN}$  bit is checked for "enabled" status. If the  $\overline{OSCEN}$  bit is enabled and the oscillator is not active, the OSCF bit is set. The user should check for this condition and then WRITE a 0 to clear the flag. It should be noted that in addition to setting the OSCF flag bit, the time registers are reset to the "Base Time" (see the section Setting the Clock on page 6), which is the value last written to the timekeeping registers. The Control/Calibration register and the  $\overline{OSCEN}$  bit are not affected by the oscillator failed condition.

If the voltage on the backup supply (either  $V_{RTCcap}$  or  $V_{RTCbat}$ ) falls below their minimum level, the oscillator may fail, leading to the oscillator failed condition, which can be detected when system power is restored.

The value of OSCF should be reset to 0 when the time registers are written for the first time. This initializes the state of this bit which may have become set when the system was first powered on.

#### Calibrating the Clock

The RTC is driven by a quartz-controlled oscillator with a nominal frequency of 32.768 kHz. Clock accuracy depends on the quality of the crystal, usually specified to 35 ppm limits at 25°C. This error could equate to +1.53 minutes in accordance with month. The CY14B101K employs a calibration circuit that can improve the accuracy to +1/–2 ppm at 25°C. The calibration circuit adds or subtracts counts from the oscillator divider circuit.

The number of pulses that are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in calibration register at 0x1FFF8. Adding counts speeds the clock up; subtracting counts slows the clock down. The calibration bits occupy the five lower order bits in the control register 8. Set these bits to represent any value between 0 and 31 in binary form. Bit D5 is a sign bit, where a "1" indicates positive calibration and a "0" indicates negative calibration. Calibration occurs within a 64 minute cycle. The first 62 minutes in the cycle may, once in accordance with minute, have one second either shortened by 128 or lengthened by 256 oscillator cycles.

If a binary "1" is loaded into the register, only the first two minutes of the 64 minute cycle will be modified; if a binary 6 is loaded, the first 12 will be affected, and so on. Therefore, each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125,829,120 actual oscillator cycles. That is 4.068 or –2.034 ppm of adjustment in accordance with calibration step in the calibration register.

In order to determine how to set the calibration one may set the CAL bit in the flags register at 0x1FFF0 to 1, which causes the INT pin to toggle at a nominal 512 Hz. Any deviation measured from the 512 Hz indicates the degree and direction of the required correction. For example, a reading of 512.010124 Hz would indicate a +20 ppm error, requiring a -10 (001010) to be loaded into the calibration register. Note that setting or changing the calibration register does not affect the frequency test output frequency.

#### **Alarm**

The alarm function compares user programmed values to the corresponding time-of-day values. When a match occurs, the alarm event occurs. The alarm drives an internal flag, AF, and may drive the INT pin if desired.

There are four alarm match fields. They are date, hours, minutes, and seconds. Each of these fields also has a match bit that is used to determine if the field is used in the alarm match logic. Setting the match bit to "0" indicates that the corresponding field will be used in the match process.

Depending on the match bits, the alarm can occur as specifically as one particular second on one day of the month, or as frequently as once in accordance with second continuously. The MSB of each alarm register is a match bit. Selecting none of the match bits (all 1s) indicates that no match is required. The alarm occurs every second. Setting the match select bit for seconds to "0" causes the logic to match the seconds alarm value to the current time of day. Since a match occurs for only one value in accordance with minute, the alarm occurs once in accordance with minute. Likewise, setting the seconds and minutes match bits causes an exact match of these values. Thus, an alarm occurs once in accordance with hour. Setting seconds, minutes, and hours causes a match once in accordance with day. Lastly, selecting all match values causes an exact time and date match. Selecting other bit combinations will not produce meaningful results; however the alarm circuit should follow the functions described.

There are two ways a user can detect an alarm event, by reading the AF flag or monitoring the INT pin. The AF flag in the flags register at 0x1FFF0 will indicate that a date and time match has occurred. The AF bit will be set to 1 when a match occurs. Reading the Flags/Control register clears the alarm flag bit (and all others). A hardware interrupt pin may also be used to detect an alarm event.

#### **Watchdog Timer**

The watchdog timer is a free running down counter that uses the 32-Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator must be running for the watchdog to function. It begins counting down from the value loaded in the watchdog timer register.

The counter consists of a loadable register and a free-running counter. On power up, the watchdog timeout value in register 0x1FFF7 is loaded into the counter load register. Counting begins on power up and restarts from the loadable value any time the watchdog strobe (WDS) bit is set to 1. The counter is

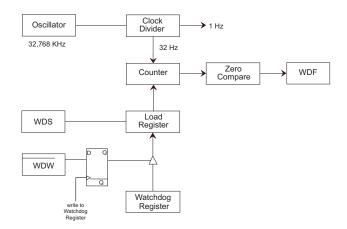


compared to the terminal value of 0. If the counter reaches this value, it causes an internal flag and an optional interrupt output. You can prevent the timeout interrupt by setting WDS bit to 1 before the counter reaching 0. This causes the counter to be reloaded with the watchdog timeout value and to be restarted. As long as the user sets the WDS bit before the counter reaching the terminal value, the interrupt and flag never occurs.

Write new timeout values by setting the watchdog WRITE bit to 0. When the WDW is 0 (from the previous operation), new writes to the watchdog timeout value bits D5–D0 allow the timeout value to be modified. When WDW is a 1, writes to bits D5 – D0 will be ignored. The WDW function allows a user to set the WDS bit without concern that the watchdog timer value will be modified. A logical diagram of the watchdog timer is shown in *Figure* 3. Note that setting the watchdog timeout value to 0 would be otherwise meaningless and therefore disables the watchdog function.

The output of the watchdog timer is a flag bit WDF that is set if the watchdog is allowed to timeout. The flag is set upon a watchdog timeout and cleared when the Flags/Control register is READREAD by the user. The user can also enable an optional interrupt source to drive the INT pin if the watchdog timeout occurs.

Figure 3. Watchdog Timer Block Diagram



#### **Power Monitor**

The CY14B101K provides a power management scheme with power fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low  $V_{CC}$  access. The power monitor is based on an internal band gap reference circuit that compares the  $V_{CC}$  voltage to various thresholds.

As described in the AutoStore section previously, when  $V_{SWITCH}$  is reached as  $V_{CC}$  decays from power loss, a data store operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from  $V_{CC}$  to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source no data may be read or written and the clock functions are not available to the user. The clock continues to operate in the background. Updated clock data is available to the user after VCC has been restored

to the device and tHRECALL delay (see AutoStore/Power Up RECALL on page 16).

#### Interrupts

The CY14B101K provides three potential interrupt sources. They include the watchdog timer, the power monitor, and the clock/calendar alarm. Individually enable each and assign to drive the INT pin. In addition, each has an associated flag bit that the host processor can use to determine the cause of the interrupt. Some of the sources have additional control bits that determine functional behavior. In addition, the pin driver has three bits that specify its behavior when an interrupt occurs.

The three interrupts each have a source and an enable. Both the source and the enable must be active (true high) in order to generate an interrupt output. Only one source is necessary to drive the pin. The user can identify the source by reading the Flags/Control register, which contains the flags associated with each source. All flags are cleared to 0 when the register is READ. The flags will be cleared only after a complete read cycle (WE high); The power monitor has two programmable settings that are explained in the power monitor section.

Once an interrupt source is active, the pin driver determines the behavior of the output. It has two programmable settings as shown in the following section. Pin driver control bits are located in the Interrupts register.

According to the programming selections, the pin can be driven in the backup mode for an alarm interrupt. In addition, the pin can be an active LOW (open drain) or an active HIGH (push pull) driver. If programmed for operation during backup mode, it can only be active LOW. Lastly, the pin can provide a one shot function so that the active condition is a pulse or a level condition. In one shot mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In level mode, the pin goes to its active polarity until the Flags/Control register is read by the user. This mode is intended to be used as an interrupt to a host microcontroller. The Interrupt register is initialized to 00h. The control bits are summarized as follows:

Watchdog Interrupt Enable – WIE. When set to 1, the watchdog timer drives the INT pin as well as an internal flag when a watchdog timeout occurs. When WIE is set to 0, the watchdog timer affects only the internal flag.

**Alarm Interrupt Enable – AIE.** When set to 1, the alarm match drives the INT pin as well as an internal flag. When set to 0, the alarm match only affects to internal flag.

**Power Fail Interrupt Enable – PFE**. When set to 1, the power fail monitor drives the pin as well as an internal flag. When set to 0, the power fail monitor affects only the internal flag.

**High/Low – H/L**. When set to a 1, the INT pin is active high and the driver mode is push-pull. The INT pin can drive high only when  $V_{CC} > V_{SWITCH}$ . When set to a 0, the INT pin is active LOW and the drive mode is open drain. Active LOW (open drain) is operational even in battery backup mode.

**Pulse/Level – P/L**. When set to a 1 and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a 0, the INT pin is driven high or low (determined by H/L) until the Flags/Control register is READd.

When an enabled interrupt source activates the INT pin, an external host can READ the Flags/Control register to determine the cause. Remember that all flags will be cleared



when the register is READ. If the INT pin is programmed for level mode, then the condition clears and the INT pin returns to its inactive state. If the pin is programmed for pulse mode, then reading the flag also clears the flag and the pin. The pulse will not complete its specified duration if the Flags/Control register is READ. If the INT pin is used as a host reset, then the Flags/Control register should not be READ during a reset.

During a power on reset with no battery, the interrupt register is automatically loaded with the value 24h. This causes power fail interrupt to be enabled with an active LOW pulse.

**Flags Register –** The Flags register has three flag bits: WDF, AF, and PF. These flag bits are initialized to 00h. These flags are set by the watchdog timeout, alarm match, or power fail monitor respectively. The processor can either poll this register or enable interrupts to be informed when a flag is set. The flags are automatically reset once the register is READ.

### **RTC Recommended Component Configuration**

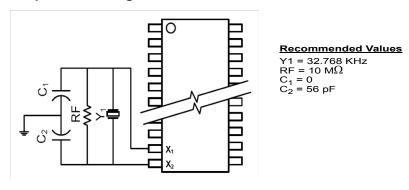
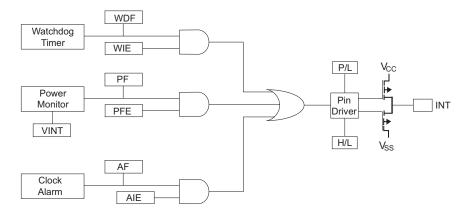


Figure 4. Interrupt Block Diagram



WDF - Watchdog Timer Flag

WIE - Watchdog Interrupt

Enable

PF - Power F ail Flag

PFE - Power Fail Enable

AF - Alarm Flag

AIE - Alarm Interrupt Enable

P/L - Pulse Level

H/L - High/Low



Table 3. RTC Register Map

Pogiotor				BCD	Format Da	ta			Function/Panga	
Register	D7	D6	D5	D4	D3	D2	D1	D0	- Function/Range	
0x1FFFF		10s	Years			Y	ears		Years: 00 – 99	
0x1FFFE	0	0	0	10s Months					Months: 01 – 12	
0x1FFFD	0	0	10s Day	of Month		Day C	of Month		Day of Month: 01 – 31	
0x1FFFC	0	0	0	0	0		Day of w	eek	Day of week: 01 – 07	
0x1FFFB	0	0	10s F	lours		Н	ours		Hours: 00 – 23	
0x1FFFA	0	1	0s Minute	s		Mi	nutes		Minutes: 00 – 59	
0x1FFF9		1	0s Second	conds Seconds				Seconds: 00 – 59		
0x1FFF8	OSCEN	0	Cal Sign			Calibration	on		Calibration Values [4]	
0x1FFF7	WDS	WDW		•	V	VDT			Watchdog <sup>[4]</sup>	
0x1FFF6	WIE	AIE	PFE	0	H/L	P/L	0	0	Interrupts <sup>[4]</sup>	
0x1FFF5	M	0	10s Alar	m Date		Alar	m Day		Alarm, Day of Month: 01 – 31	
0x1FFF4	M	0	10s Alarm Hours		ours Alarm Hours		urs Alarm Hours			Alarm, Hours: 00 – 23
0x1FFF3	M	10 /	Alarm Min	utes	Alarm Minutes			Alarm, Minutes: 00 – 59		
0x1FFF2	M	10 /	Alarm Min	nutes Alarm, Seconds			Alarm, Seconds: 00 – 59			
0x1FFF1		10s C	enturies		Centuries			Centuries: 00 – 99		
0x1FFF0	WDF	AF	PF	OSCF	0	CAL	W	R	Flags <sup>[4]</sup>	

Table 4. Register Map Detail

				Time Keepi	ng – Years			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFFF		10s	Years			Ye	ears	
				ear. Lower nibbles from 0 to 9. 1				le contains the
				Time Keepin	g – Months			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFFE	0	0	0	10s Month		Мс	onths	
				er nibble contai ates from 0 to 1				9; upper nibble
				Time Keepi	ng – Date			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFFD	0 0 10s Day of Month Day of Month							
	upper nibble			month. Lower of perates from 0				
				Time Keep	ing – Day			
	D7 D6 D5 D4 D3 D2 D1 D0						D0	
0x1FFFC	0	0 0 0 0 Day of Week						(
	Lower nibble contains a value that correlates to day of the week. Day of the week is a ring counter that counts find the returns to 1. The user must assign meaning to the day value, as the day is not integrated with the day value, as the day is not integrated with the day value.							

#### Note

<sup>4.</sup> This register contains a binary, not BCD, value. .



Table 4. Register Map Detail (continued)

				Time Keepii	ng – Hours			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFFB	12/24	0	10s H	Hours		H	ours	I
	Contains the BCD value of hours in 24 hour format. Lower nibble contains the lower digit and operates from 0 to upper nibble (two bits) contains the upper digit and operates from 0 to 2. The range for the register is $0-23$ .							
				Time Keepin	g – Minutes			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFFA	0		10s Minutes			Mir	nutes	
				nibble contains ites from 0 to 5.				upper nibble
				Time Keeping	g – Seconds			
	D7	D6	D5	D4	D3	D2	D1	D0
0x1FFF9	0		10s Seconds			Sec	conds	
				r nibble contain 0 to 5. The ran				; upper nibble
				Calibratio	n/Control			
0X1FFF8	D7	D6	D5	D4	D3	D2	D1	D0
	OSCEN	0	Calibration Sign			Calibration		
OSCEN				ator is halted. V ige. On a no ba				g the oscillator
Calibration Sign	Determines i	f the calibration	n adjustment is	applied as an a	iddition to or a	as a subtractio	n from the tim	ne base.
Calibration	These five bi	ts control the c	alibration of the	e clock.				
				WatchDo	g Timer			
0x1FFF7	D7	D6	D5	D4	D3	D2	D1	D0
	WDS	WDW			WI	T		
WDS	Watchdog St bit is cleared a 0.	robe. Setting the automatically of	nis bit to 1 reload once the watch	ds and restarts to dog timer is rese	the watchdog et. The WDS b	timer. Setting oit is WRITE or	the bit to 0 has nly. Reading it	s no affect. The always returns
WDW	Watchdog Write Enable. Setting this bit to 1 masks the watchdog timeout value (WDT5–WDT0) so it cannot be written. This allows the user to strobe the watchdog without disturbing the timeout value. Setting this bit to 0 allows bits 5 – 0 to be written on the next WRITE to the watchdog register. The new value will be loaded on the next internal watchdog clock after the WRITE cycle is complete. This function is explained in more detail in the watchdog timer section.							
WDT	a multiplier o maximum tin	f the 32 Hz cou neout is 2 seco	int (31.25 ms). 3 nds (setting of 3	g timer interval in The minimum ra 3 Fh). Setting the cleared to 0 or	ange or timeou ie watchdog ti	ut value is 31.2 mer register to	25 ms (a settin	ng of 1) and the



Table 4. Register Map Detail (continued)

				Interrupt Sta	tus/Control			
0x1FFF6	D7	D6	D5	D4	D3	D2	D1	D0
	WIE	AIE	PFIE	0	H/L	P/L	0	0
WIE				and a watchdo e watchdog tim				es the INT pin
AIE		pt Enable. Who		alarm match dri	ves the INT pi	n as well as th	ne AF flag. Wh	en set to 0, the
PFIE			et to 1, the alar	m match drives	the INT pin a	s well as the /	AF flag. When	set to 0, the
0	Reserved Fo	r Future Use.						
H/L	High/Low. W	hen set to a 1,	the INT pin is o	driven active hig	h. When set t	o 0, the INT p	in is open dra	in, active LOW.
P/L								r approximately egister is READ.
				Alarm	– Day			
0x1FFF5	D7	D6	D5	D4	D3	D2	D1	D0
0.11113	M	0	10s Ala	rm Date		Aları	m Date	
	Contains the	alarm value fo	r the date of th	e month and the	e mask bit to s	select or dese	lect the date v	alue.
M		ng this bit to 0 of to ignore the o		value to be us	ed in the alarr	n match. Setti	ng this bit to 1	causes the
				Alarm –	Hours			
0x1FFF4	D7	D6	D5	D4	D3	D2	D1	D0
UX IFFF4	M 0 10s Alarm Hours Alarm Hours							
	Contains the	alarm value fo	r the hours and	I the mask bit to	select or des	elect the hour	rs value.	
M		ng this bit to 0 of to ignore the h		rs value to be u	sed in the ala	rm match. Set	ting this bit to	1 causes the
				Alarm –	Minutes			
0x1FFF3	D7	D6	D5	D4	D3	D2	D1	D0
UXIFFF3	M	0	10s Alarr	n Minutes		Alarm	Minutes	
	Contains the	alarm value fo	r the minutes a	nd the mask bi	t to select or d	eselect the m	inutes value.	
M		ng this bit to 0 co to ignore the r		ites value to be	used in the al	arm match. S	etting this bit t	o 1 causes the
				Alarm – S	Seconds			
0x1FFF2	D7	D6	D5	D4	D3	D2	D1	D0
UXIFFFZ	M	0	10s Alarm	Seconds		Alarm	Seconds	
	Contains the	alarm value fo	r the seconds a	and the mask b	it to select or o	deselect the s	econd value.	
M		ng this bit to 0 of to ignore the s		ond value to be	used in the al	arm match. S	etting this bit t	o 1 causes the
				Time Keeping	– Centuries			
0x1FFF1	D7	D6	D5	D4	D3	D2	D1	D0
	0	0	10s Ce	enturies		Cer	nturies	•



Table 4. Register Map Detail (continued)

				Fla	gs			
0x1FFF0	D7	D6	D5	D4	D3	D2	D1	D0
	WDF	AF	PF	OSCF	0	CAL	W	R
WDF				is set to 1 wher ne Flags/Contro			wed to reach 0	) without being
AF				when the time a the Flags/Contr			stored in the al	larm registers
PF			only bit is set to I register is RE		falls below the	e power fail th	reshold V <sub>SWIT</sub>	<sub>CH</sub> . It is cleared
OSCF	This indicate	s that time cou		only if the oscilla er valid. The us wer cycles.				
CAL				square wave is on power		NT pin. When	set to 0, the IN	NT pin resumes
W	Write Time. Setting the W bit to 1 freeze updates of the timekeeping registers. The user can then WRITE them with updated values. Setting the W bit to 0 causes the contents of the time registers to be transferred to the timekeeping counters. The W-bit enables writes to RTC, Alarm, Calibration, Interrupt, and Flag registers.							
R	register. The	user can then	READ them wi	a static image of thout concerns capture, so the	over changing	yalues caus	ing system err	ors. The R bit



# **Maximum Ratings**

Package Power Dissipation Capability (T <sub>A</sub> = 25°C)	,
Surface Mount Pb Soldering Temperature (3 Seconds)+260°C	
Output Short Circuit Current [5]	
Static Discharge Voltage > 2001V (in accordance with MIL-STD-883, Method 3015)	
Latch Up Current > 200 mA	

# **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to +70°C	2.7V to 3.6V
Industrial	–40°C to +85°C	2.7V to 3.6V

#### **DC Electrical Characteristics**

Over the Operating Range (VCC = 2.7V to 3.6V) [6, 7, 8]

Parameter	Description	Test Conditions		Min	Max	Unit
I <sub>CC1</sub>	Average V <sub>CC</sub> Current	$t_{RC}$ = 25 ns $t_{RC}$ = 35 ns $t_{RC}$ = 45 ns	Commer cial		65 55 50	mA mA mA
		Dependent on output loading and cycle rate. Values obtained without output loads.  I <sub>OUT</sub> = 0 mA.	Industrial		55 (t <sub>RC</sub> = 45 ns)	mA mA mA
I <sub>CC2</sub>	Average V <sub>CC</sub> Current during STORE	All Inputs Do Not Care, V <sub>CC</sub> = Max Average current for duration t <sub>STORE</sub>			6	mA
I <sub>CC3</sub>	Average V <sub>CC</sub> Current at t <sub>AVAV</sub> = 200 ns, 3V, 25°C typical	WE > (V <sub>CC</sub> – 0.2). All other inputs cyclind Dependent on output loading and cycle Values obtained without output loads.			10	mA
I <sub>CC4</sub>	Average V <sub>CAP</sub> Current during AutoStore Cycle	All Inputs Do Not Care, V <sub>CC</sub> = Max Average current for duration t <sub>STORE</sub>			3	mA
I <sub>SB</sub>	V <sub>CC</sub> Standby Current	$\overline{\text{WE}}$ > (V <sub>CC</sub> - 0.2). All others V <sub>IN</sub> < 0.2V > (V <sub>CC</sub> -0.2V). Standby current level after a tile cycle is complete. Inputs are static. f = 0 MHz	or er nonvol-		3	mA
I <sub>IX</sub>	Input Leakage Current	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}$		-1	+1	μΑ
I <sub>OZ</sub>	Off State Output Leakage Current	$V_{CC} = Max, V_{SS} \le V_{IN} \le V_{CC}, \overline{CE} \text{ or } \overline{OE}$	> V <sub>IH</sub>	<b>–</b> 1	+1	μА
$V_{IH}$	Input HIGH Voltage <sup>[9]</sup>			2.0	V <sub>CC</sub> + 0.3	V
$V_{IL}$	Input LOW Voltage			V <sub>SS</sub> – 0.5	0.8	V
V <sub>OH</sub>	Output HIGH Voltage	I <sub>OUT</sub> = –2 mA		2.4		V
$V_{OL}$	Output LOW Voltage	I <sub>OUT</sub> = 4 mA			0.4	V
$V_{CAP}$	Storage Capacitor	Between V <sub>CAP</sub> pin and V <sub>SS</sub> , 5V rated		17	120	μF

#### Notes

- 5. Outputs shorted for no more than one second. No more than one output shorted at a time.
- 6. Typical conditions for the active current shown at the beginning of the data sheet are average values at 25°C (room temperature), and  $V_{CC}$  = 3V. Not 100% tested.
- 7. The HSB pin has  $I_{OUT} = -10 \mu A$  for  $V_{OH}$  of 2.4 V, this parameter is characterized but not tested.
- 8. The INT pin is open drain and does not source or sink current when interrupt register bit D3 is low.
- 9.  $V_{IH}$  changes by 100 mV when  $V_{CC} > 3.5V$ .



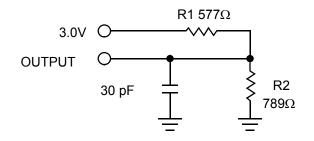
# Capacitance [10]

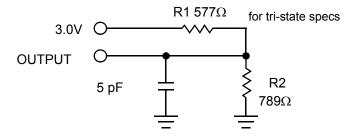
Parameter	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	7	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 0$ to 3.0 V	7	pF

# Thermal Resistance [10]

Parameter	Description	Test Conditions	48-SSOP	Unit
$\Theta_{JA}$	Thermal Resistance (junction to ambient)	Test conditions follow standard test methods and procedures for measuring thermal impedance, in	TBD	°C/W
$\Theta_{\sf JC}$	Thermal Resistance (junction to case)	accordance with EIA/JESD51.	TBD	°C/W

### **AC Test Loads**





# **AC Test Conditions**

Input Pulse Levels	0 V to 3 V
Input Rise and Fall Times (10% - 90%)	<u>&lt;</u> 5 ns
Input and Output Timing Reference Levels	1.5 V

Note

<sup>10.</sup> These parameters are guaranteed but not tested.



# **AC Switching Characteristics**

Parameter			25 ns	s part	35 ns	s part	45 ns	s part	Unit	
Cypress Parameter	Alt. Parameter	Description	Min	Max	Min	Max	Min	Max	-	
SRAM REA	D Cycle									
t <sub>ACE</sub>	t <sub>ACS</sub>	Chip Enable Access Time		25		35		45	ns	
t <sub>RC</sub> [11]	t <sub>RC</sub>	Read Cycle Time	25		35		45		ns	
t <sub>AA</sub> [12]	t <sub>AA</sub>	Address Access Time		25		35		45	ns	
t <sub>DOE</sub>	t <sub>OE</sub>	Output Enable to Data Valid		12		15		20	ns	
t <sub>OHA</sub> [12]	t <sub>OH</sub>	Output Hold After Address Change	3		3		3		ns	
t <sub>LZCE</sub> <sup>[13]</sup>	$t_{LZ}$	Chip Enable to Output Active	3		3		3		ns	
t <sub>HZCE</sub> [13]	$t_{HZ}$	Chip Disable to Output Inactive		10		13		15	ns	
t <sub>LZOE</sub> [13]	t <sub>OLZ</sub>	Output Enable to Output Active	0		0		0		ns	
t <sub>HZOE</sub> [13]	t <sub>OHZ</sub>	Output Disable to Output Inactive		10		13		15	ns	
t <sub>PU</sub> <sup>[10]</sup>	t <sub>PA</sub>	Chip Enable to Power Active	0		0		0		ns	
t <sub>PD</sub> <sup>[10]</sup>	t <sub>PS</sub>	Chip Disable to Power Standby		25		35		45	ns	
SRAM WRIT	TE Cycle		•				•	•		
t <sub>WC</sub>	t <sub>WC</sub>	Write Cycle Time	25		35		45		ns	
t <sub>PWE</sub>	t <sub>WP</sub>	Write Pulse Width	20		25		30		ns	
t <sub>SCE</sub>	t <sub>CW</sub>	Chip Enable To End of Write	20		25		30		ns	
t <sub>SD</sub>	t <sub>DW</sub>	Data Setup to End of Write	10		12		15		ns	
t <sub>HD</sub>	t <sub>DH</sub>	Data Hold After End of Write	0		0		0		ns	
t <sub>AW</sub>	t <sub>AW</sub>	Address Setup to End of Write	20		25		30		ns	
t <sub>SA</sub>	t <sub>AS</sub>	Address Setup to Start of Write	0		0		0		ns	
t <sub>HA</sub>	t <sub>WR</sub>	Address Hold After End of Write	0		0		0		ns	
t <sub>HZWE</sub> [13, 14]	$t_{WZ}$	Write Enable to Output Disable		10		13		15	ns	
t <sub>LZWE</sub> [13]	t <sub>OW</sub>	Output Active after End of Write	3		3		3		ns	

# **AutoStore/Power Up RECALL**

Parameter	Description	CY14	B101K	Unit ms ms	
	Description	Min	Max		
t <sub>HRECALL</sub> [15]	Power Up RECALL Duration		20	ms	
t <sub>STORE</sub> [16, 17]	STORE Cycle Duration		12.5	ms	
V <sub>SWITCH</sub>	Low Voltage Trigger Level		2.65	V	
t <sub>VCCRISE</sub>	VCC Rise Time	150		μ\$	

#### Notes

- 11. WE must be HIGH during SRAM READ cycles.
- 12. Device is continuously selected with  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  both low.
- 13. Measured ±200 mV from steady state output voltage.

- 14. If WE is low when CE goes low, the outputs remain in the high impedance state.

  15. t<sub>HRECALL</sub> starts from the time V<sub>CC</sub> rises above V<sub>SWITCH</sub>.

  16. If an SRAM WRITE has not taken place since the last nonvolatile cycle, no STORE takes place.

  17. Industrial grade devices require 15 ms max.



# Software Controlled STORE/RECALL Cycle [18, 19, 20]

Parameter	Description	25 ns	part	35 ns	part	45 ns	part	Unit	
Parameter	Description	Min	Max	Min	Max	Min	Max	Unit	
t <sub>RC</sub>	STORE/RECALL Initiation Cycle Time	25		35		45		ns	
t <sub>AS</sub>	Address Setup Time	0		0		0		ns	
t <sub>CW</sub>	Clock Pulse Width	20		25		30		ns	
t <sub>GHAX</sub>	Address Hold Time	1		1		1		ns	
t <sub>RECALL</sub>	RECALL Duration		100		100		100	μS	
t <sub>SS</sub> [21, 22]	Soft Sequence Processing Time		70		70		70	μS	

# **Hardware STORE Cycle**

Parameter	Description	CY14B101K		Unit
	Description	Min	Max	Ollit
t <sub>DELAY</sub> [23]	Time allowed to complete SRAM Cycle	1	70	μs
t <sub>HLHX</sub>	Hardware STORE Pulse Width	15		ns

#### **RTC Characteristics**

Parameters	Description	Test Conditions		Min	Max	Units
I <sub>BAK</sub> [24]	RTC Backup Current		Commercial		300	nA
			Industrial		350	nA
V <sub>RTCbat</sub> [25]	RTC Battery Pin Voltage		Commercial	1.8	3.3	V
			Industrial	1.8	3.3	V
V <sub>RTCcap</sub> <sup>[26]</sup>	RTC Capacitor Pin Voltage		Commercial	1.2	2.7	V
			Industrial	1.2	2.7	V
tocs	RTC Oscillator Time to Start	@Min Temperature from Power up or Enable	Commercial		10	sec
		@25°C Temperature from Power up or Enable	Commercial		5	sec
		@Min Temperature from Power up or Enable	Industrial		10	sec
		@25°C Temperature from Power up or Enable	Industrial		5	sec

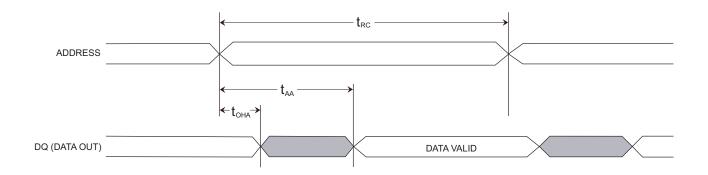
#### Notes

- 18. The software sequence is clocked with  $\overline{\text{CE}}$  controlled or  $\overline{\text{OE}}$  controlled READs.
- 19. The six consecutive addresses must be READ in the order listed in the mode selection table. WE must be HIGH during all six consecutive cycles.
- 20. A  $600\Omega$  resistor must be connected to  $\overline{\text{HSB}}$  to use the software command.
- 21. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register the command.
- 22. Commands like STORE and RECALL lock out IO until operation is complete which further increases this time. See the specific command.
- 23. READ and WRITE cycles in progress before HSB are given this amount of time to complete.
- 24. From either V<sub>RTCcap</sub> or V<sub>RTCbat</sub>.
- 25. Typical = 3.0V during normal operation.
- 26. Typical = 2.4V during normal operation.

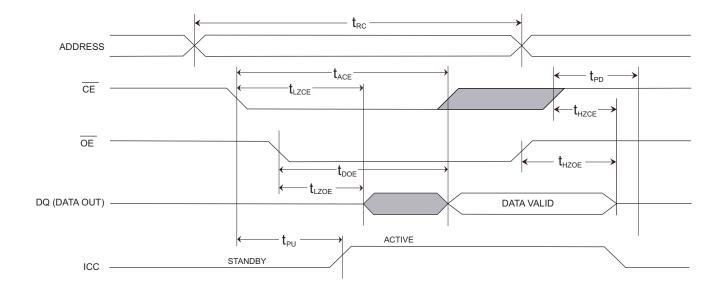


# **Switching Waveforms**

SRAM Read Cycle 1 (address controlled) [11, 12, 27]



SRAM Read Cycle 2 ( $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  controlled) [11, 27]



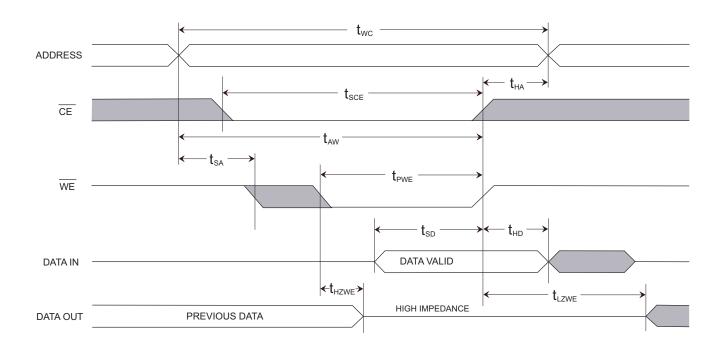
#### Note

<sup>27.</sup> HSB must remain HIGH during READ and WRITE cycles.

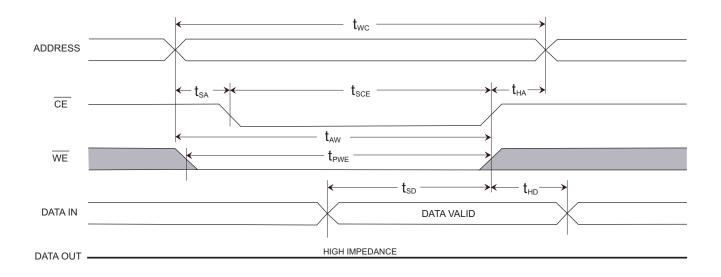


# Switching Waveforms (continued)

# SRAM WRITE Cycle 1 (WE controlled) [27, 28]



# SRAM WRITE Cycle 2 (CE controlled)



#### Note

28.  $\overline{\text{CE}}$  or  $\overline{\text{WE}}$  must be > V<sub>IH</sub> during address transitions.



# Switching Waveforms (continued)

Figure 5. AutoStore/Power Up RECALL

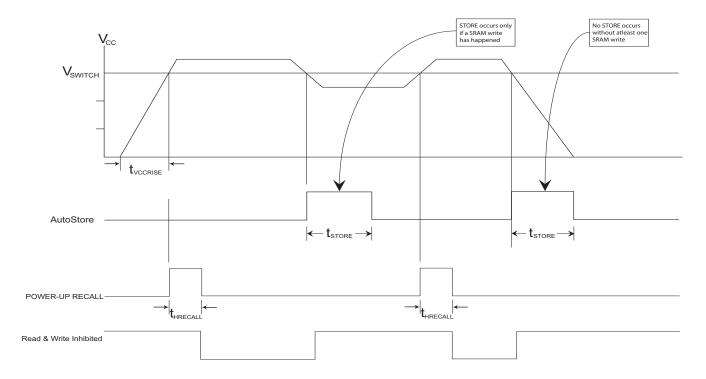
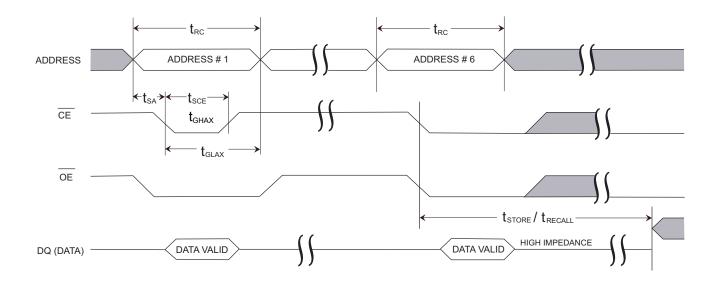


Figure 6. CE-Controlled Software STORE/RECALL Cycle [19]





# Switching Waveforms (continued)

Figure 7. OE-Controlled Software STORE/RECALL Cycle [19]

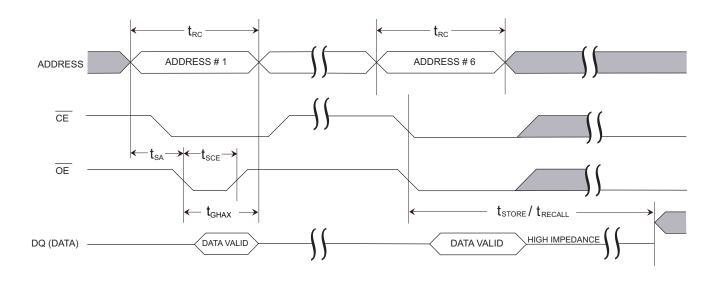


Figure 8. Hardware STORE Cycle

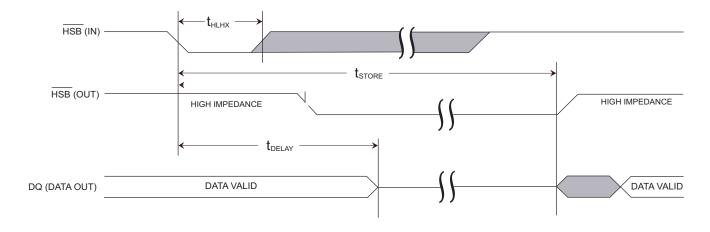
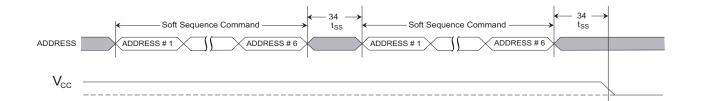
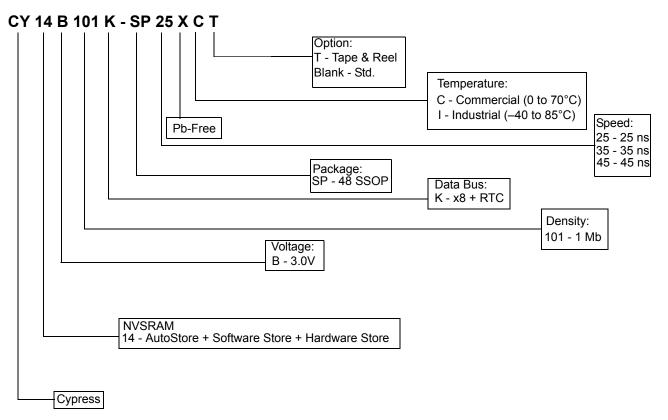


Figure 9. Soft Sequence Processing [21, 22]





### PART NUMBERING NOMENCLATURE



# **Ordering Information**

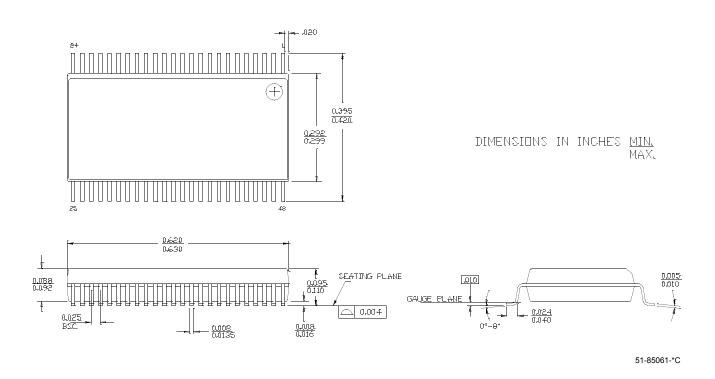
All of the above mentioned parts are of "Pb-free" type. Shaded areas contain advance information. Contact your local Cypress sales representative for availability of these parts.

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B101K-SP25XCT	51-85061	48-pin SSOP	Commercial
35	CY14B101K-SP35XCT	51-85061	48-pin SSOP	Commercial
45	CY14B101K-SP45XCT	51-85061	48-pin SSOP	Commercial
45	CY14B101K-SP45XIT	51-85061	48-pin SSOP	Industrial
	CY14B101K-SP45XI	51-85061	48-pin SSOP	



# **Package Diagram**

Figure 10. 48-Pin Shrunk Small Outline Package, 51-85061



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# **Document History Page**

REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	425138	See ECN	TUP	New Data Sheet
*A	437321	See ECN	TUP	Show Data Sheet on External Web
*B	471966	See ECN	TUP	Changed I <sub>CC3</sub> from 5 mA to 10 mA Changed ISB from 2 mA to 3 mA Changed V <sub>IH(min)</sub> from 2.2V to 2.0V Changed t <sub>RECALL</sub> from 40 µs to 100 µs Changed Endurance from 1Million Cycles to 500K Cycles Changed Data Retention from 100 Years to 20 Years Added Soft Sequence Processing Time Waveform Updated Part Numbering Nomenclature and Ordering Information Added RTC Characteristics Table Added RTC Recommended Component Configuration
*C	503272	See ECN	PCI	Changed from Advance to Preliminary Changed the term "Unlimited" to "Infinite" Changed Endurance from 500K Cycles to 200K Cycles Added temperature spec. to Data Retention - 20 years at 55°C Removed Icc <sub>1</sub> values from the DC table for 25 ns and 35 ns Industrial Gra Changed Icc <sub>2</sub> value from 3 mA to 6 mA in the DC Table Added a footnote on V <sub>IH</sub> Added footnote 18 related to using the software command Changed V <sub>SWITCH(min)</sub> from 2.55V to 2.45V Updated Part Nomenclature Table and Ordering Information Table
*D	597002	See ECN	TUP	Removed $V_{SWITCH(min)}$ spec from the AutoStore/Power Up RECALL Tall Changed $t_{GLAX}$ spec from 20 ns to 1 ns Added $t_{DELAY(max)}$ spec of 70 $\mu$ s in the Hardware STORE Cycle Table Removed $t_{HLBL}$ specification Changed $t_{SS}$ specification form 70 $\mu$ s (min) to 70 $\mu$ s (max) Changed $V_{CAP(max)}$ from 57 $\mu$ F to 120 $\mu$ F
*E	688776	See ECN	VKN	Added footnote 7 related to HSB Added footnote 8 related to INT pin Changed t <sub>GLAX</sub> to t <sub>GHAX</sub> Removed ABE bit from interrupt register